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# **CONTENTS**

## **Mini-Colloquium on Nanoelectronics**

### **Silicon Nanodevices for Intelligent Communications**

S. Oda..... 3

### **Non-Volatility by Spin in Modern Nanoelectronics**

V. Sverdlov, A. Makarov, J. Weinbub and S. Selberherr..... 7

### **Photovoltaics as Macroelectronics Applying Nanostructures as Nanoelectronics**

M. Topič, M. Jošt, M. Sever, B. Lipovšek, J. Krč..... 15

### **Innovative Bipolar-CMOS Integration for RF Communication Circuits with Low-Cost High-Performance Horizontal Current Bipolar Transistor (HCBT)**

T. Suligoj, M. Koričić, J. Žilak ..... 19

## **Plenary Sessions**

### **SiC Power MOSFETs: The Current Status and the Potential for Future Development**

S. Dimitrijev..... 29

### **An Overview of the Modeling and Simulation of the Single Event Transients at the Circuit Level**

M. Andjelkovic, A. Ilic, Z. Stamenkovic, M. Krstic, R. Kraemer ..... 35

### **Basic Trends in Electronic Components Product Range Development: Radiation Hardness Aspects**

A.Y. Nikiforov, D.V. Boychenko, V.A. Telets, A.A. Smolin, V.V. Elesin, A.V. Ulanova,  
L.N. Kessarinskiy..... 45

### **The Scaling Issues of Subnanometer EOT Gate Dielectrics for the Ultimate Nano CMOS Technology**

J. Zhang, H. Wong, V. Filip..... 49

### **High Sensitivity Magnetic Sensors Compatible with Bulk Silicon and SOI IC Technology**

P. Igić, O. Kryvchenkova, S. Faramehr, S. Batcup, N. Janković ..... 55

## **Session Device Physics, Technology and Testing**

<b>Nanoelectronic Graphene Devices</b>	
P. I. Hagouel, I.G. Karafyllidis.....	63
<b>Functional Role of Ca<sup>2+</sup> Currents within the Stereocilia as Bio-MEMS: A Modeling Study</b>	
D.L. Sekulic, M.V. Sataric, A.V. Joza .....	67
<b>Memristor state transition in reconfigurable microwave filter</b>	
I. Marković, M. Potrebić, D. Tošić .....	71
<b>Simulation of Solo GaN IGBTs</b>	
S. Faramehr, P. Igić .....	75
<b>A Case Study of C-V Hysteresis Instability in Metal-High-k-Oxide-Silicon Devices with ZrO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Zr<sub>2</sub>O<sub>2</sub> Stack as a Charge Trapping Layer</b>	
A. Skeparovski, D. Spassov, A. Paskaleva, N. Novkovski .....	79
<b>A Comparison of the Tri-Layer Transmission Line Model and a Finite Element Model for Ohmic Contact Analysis</b>	
F. Algahtani, S. Luong, Y. Pan, M.S. Alnassar, A. Holland .....	83
<b>SOI Based Double Source Tunnel FET (DS-TFET) with High On-Current and reduced Turn-on Voltage</b>	
N. Bagga, A. Kumar and S. Dasgupta.....	87
<b>Formation of Short Terahertz Electromagnetic Pulses in Nonlinear Paraelectrics</b>	
V. Grimalsky, S. Koshevaya, J. Escobedo-Alatorre, E. Jatirian-Foltides .....	91

## **Session Circuits Design and Testing**

<b>Implementation of Fuzzy Logic Operators as Digital Asynchronous Circuits in CMOS Technology</b>	
T. Talaśka .....	97
<b>Parallel Matrix Multiplication in 2-gain Kalman Filter Realized in Hardware</b>	
I. Zbierska, T. Talaśka, R. Długosz .....	101
<b>Energy-Efficiency vs. Performance Optimization in Low-Power Wireless Transmission</b>	
N. Zogović .....	105
<b>Analog ASIC TID Behavior in a Temperature Range</b>	
A.Y. Borisov, L.N. Kessarinskiy, M.M. Vanzha, M.P. Belova, Y.M. Moskovskaya, D.V. Boychenko, A.Y. Nikiforov, V.V. Enns .....	109

<b>Integrated Current Sensor for Automotive Power Switches</b>	
R. Brata, A. Danchiv, L. Dobrescu, D. Dobrescu .....	113
<b>Plastic Encapsulated ICs Bonding Reliability Risk Assessment at HT Automotive Application</b>	
M. Blyzniuk, A. Devos, M. Furman .....	117

## **Poster Session**

### **Device Physics, Technology and Testing**

<b>Tailorable Effective Optical Response of Dual-metal Plasmonic Crystals</b>	
M. Obradov, J. Lamovec, I. Mladenović, Z. Jakšić, S. Vuković, G. Isić, D. Tanasković .....	123
<b>Stochastic Time Response of Adsorption-Based Micro/Nanobiosensors with a Fluidic Reaction Chamber: the Influence of Mass Transfer</b>	
I. Jokić, Z. Djurić, K. Radulović, M. Frantlović .....	127
<b>Effect of High Energy Ball Milling on the Morphology and Magnetic Properties of Powder Prepared from HD Nd<sub>2</sub>Fe<sub>14</sub>B Material</b>	
V. Jović, J. Lamovec, D. Sojer, D. Lončarević, I. Mladenović, D. Vasiljević Radović .....	131
<b>Characterization of Yttrium Orthoferrite (YFeO<sub>3</sub>) Nanoparticles as Humidity Sensor Materials at Room Temperature</b>	
D.L. Sekulic, Z. Lazarevic, C. Jovalekic, N. Romcevic .....	135
<b>On the Design of Compact Intelligent Industrial Transmitters Based on Piezoresistive MEMS Pressure Sensors</b>	
M. Frantlović, P. Poljak, I. Jokić, D. Randjelović, D. Vasiljević Radović .....	139
<b>Electrical and Charge Trapping Properties of HfO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub> Multilayer Dielectric Stacks</b>	
V. Davidović, A. Paskaleva, D. Spassov, E. Guziewicz, T. Krajewski, S. Golubović, S. Djorić-Veljković, I. Manić, D. Danković, N. Stojadinović .....	143
<b>Modelling of Threshold Voltage Shift in Pulsed NBT Stressed P-Channel Power VDMOSFETs</b>	
D. Danković, I. Manić, N. Stojadinović, Z. Prijić, S. Djorić-Veljković, V. Davidović, A. Prijić, A. Paskaleva, D. Spassov, S. Golubović .....	147
<b>GaN HEMT Small-Signal Modelling: Neural Networks versus Equivalent Circuit</b>	
Z. Marinković, G. Crupi, A. Caddemi, V. Marković .....	153
<b>Compact Thermal Modelling of Power LED Light Sources</b>	
T. Torzewicz, K. Baran, T. Raszkowski, A. Samson, H. Wachta, A. Napieralski .....	157
<b>Estimation Technique for LED Sensitivity to Structural Damage Based on Minority Carriers Lifetime Measurements</b>	
R.K. Mozhaev, M.E. Cherniak, A.V. Ulanova, A.Y. Nikiforov .....	161
<b>Power MOSFET Single Event Burnout Hardness Increasing by Neutron Preirradiation</b>	
L. Kessarinskiy, D. Boychenko, A. Nikiforov, A. Polokhov, T. Kritskaya, G. Davydov .....	165

<b>Temperature Influence on the TID effects in RadFETs</b>	
V. Felitsyn, B. Podlepetsky, A. Bakerenkov, A. Rodin, Yu. Sukhoroslova.....	167
<b>Joint Model of Dose Rate Radiation Effects in Bipolar Devices</b>	
V. Pershenkov, A. Bakerenkov, V. Telets, V. Belyakov, V. Shurenkov, V. Felitsyn, A. Rodin.....	171
<b>Numerical Computation of the Physical Shielding Factor for Different Structures of MOSFET in Gamma Irradiation Field</b>	
S. Stanković, R. Ilić, A. Jakšić, D. Nikolić, N. Kržanović .....	175
<b>Influence of High Voltage Pulse Trimming on Thick-Film Resistor Quality Indicators</b>	
I. Stanimirović, Z. Stanimirović .....	179
<b>Electrical Properties of Rare Earth Doped BaTiO<sub>3</sub> Ceramics</b>	
V. Paunović, V. Mitić, M. Đorđević, Z. Prijić.....	183
<b>Evaluation of the Mechanical and Tribological Properties of Multilayer CrN/TiN Films Deposited at Low Temperatures</b>	
L. Kolaklieva, S. Rabadzhiyska, R. Kakanakov, V. Chitanov, T. Cholakova, V. Rupetchov, G. Mishev .....	187
<b>Analysis of Low-pressure DC Breakdown in Air</b>	
E. Živanović .....	191
<b>Capacitance Model for MOSFET Operated in all Regions</b>	
A. Benfdila, A. Lakhlef.....	195
<b>Investigation on Cylindrical Gate-All-Around (GAA) Tunnel FETS Scaling</b>	
M. Kessi, A. Benfdila, A. Lakhlef.....	199

## **Session System Design and Testing**

<b>An HDL Model of a Digitally Controlled Oscillator for Rapid Digital PLL Prototyping</b>	
V. Milovanovic, B. Nikolic .....	205
<b>Low Power SAR ADC with Two-Step Switching Scheme in 65 nm Standard CMOS Process</b>	
D. Osipov, St. Paul .....	209
<b>The Implementation of Harmonic Analysis Methods in Active Power Filters Control</b>	
B. Jovanović, P. Petković, S. Milenković .....	213
<b>Comparison of the SET Sensitivity of Standard Logic Gates Designed in 130 nm CMOS Technology</b>	
M. Andjelkovic, M. Krstic, R. Kraemer .....	217
<b>Classification of Nonlinear Loads based on Artificial Neural Networks</b>	
M. Andrejević Stošović, D. Stevanović, M. Dimitrijević.....	221

<b>32-channel Self-triggered ASIC for GEM Detectors</b>	
E. Atkin, I. Bulbakov, V. Ivanov, P. Ivanov, E. Malankin, D. Normanov, S. Petrovskiy, V. Shumikhin, A. Voronin, V. Samsonov .....	225

## **Poster Session**

### **Circuit Design and Testing**

<b>Real-time Locating Systems for Smart City and Intelligent Transportation Applications</b>	
M. Banach, R. Długosz.....	231
<b>Selected Aspects and Tradeoffs in Transistor Level Implementation of Genetic Algorithms</b>	
S. Jezewski, R. Długosz.....	235
<b>Advanced Stand for Transient Thermal Measurements</b>	
T. Torzewicz, A. Sobczak, M. Janicki, A. Napieralski.....	239
<b>A Low-Latency Medium Access Control Protocol for Industrial Wireless LAN Applications</b>	
N. Odhah, K. Tittelbach-Helmrich, Z. Stamenković .....	243
<b>Comparison of On-Chip ADC Testing Techniques</b>	
A.Yu. Egorov, I.A. Mozhaev, P.V. Nekrasov, D.V. Boychenko, I.O. Loskutov .....	247
<b>SEFI Cross-section Evaluation by Fault Injection Software Approach and Hardware Detection</b>	
I.O. Loskutov, P.V. Nekrasov, I.I. Shvetsov-Shilovskiy, D.V. Boychenko, V.M. Uzhegov .....	251
<b>FRAM Test Memory Cells Radiation Hardness Research</b>	
I.I. Shvetsov-Shilovskiy, A.B. Boruzdina, A.V. Ulanova, O.M. Orlov, Y.A. Matveev, D.V. Negrov .....	255
<b>Investigation of Ionizing Transients by Femtosecond X-ray Source Ionization</b>	
M.P. Belova, L.N. Kessarinskiy, A.Y. Borisov, A.I. Chumakov, D.V. Boychenko, K.A. Ivanov, I.N. Tsymbalov, R.V. Volkov, A.B. Savel'ev.....	259
<b>Optimal Laser Wavelengths for Transient Ionizing Response Simulation of CMOS SOI Devices with 0.24 μm Design Rules</b>	
S.B. Shmakov, P.K. Skorobogatov, A.V. Ulanova, A.B. Boruzdina, G.G. Davydov, A.Y. Nikiforov .....	263
<b>Total Ionizing Dose Hardness Nondestructive Individual Estimation and Predictive Grading for Silicon-on-insulator ICs</b>	
Y.M. Moskovskaya, G.G. Davydov, A.V. Sogoyan, A.Y. Nikiforov, I.B. Yashanin .....	267
<b>Total Ionizing Dose Degradation of CMOS 8-transistor Image Sensor with Column ADC</b>	
M. Cherniak, A. Smolin, R. Mozhaev, A. Ulanova, A. Nikiforov .....	271
<b>Process Parameters Variations Influence on CMOS IC's Hardness to Total Ionizing Dose</b>	
Y.M. Moskovskaya, A.Y. Nikiforov, D.V. Bobrovskiy, A.V. Ulanova, A.A. Zhukov.....	275

<b>Battery Capacity Estimation of Wireless Sensor Node</b>	
G. Nikolić, T. Nikolić, M. Stojčev, B. Petrović, G. Jovanović .....	279
<b>Analog Device Design for Testability in the Case of Oscillation Based Testing</b>	
M. Petrović, M. Milić .....	283
<b>The Prediction for Single Event Latchup Sensitivity Parameters of Digital CMOS ICs Based on its Technological Features</b>	
A.E. Rudenkov, A.O. Akhmetov, D.V. Bobrovsky, A.I. Chumakov, A.V. Yanenko, V.M. Uzhegov .....	287

## **Poster Session**

### **System Design and Testing**

<b>Asynchronous Early Output Section-Carry Based Carry Lookahead Adder with Alias Carry Logic</b>	
P. Balasubramanian, C. Dang, D.L. Maskell, K. Prasad.....	293
<b>Approximate Ripple Carry and Carry Lookahead Adders – A Comparative Analysis</b>	
P. Balasubramanian, C. Dang, D.L. Maskell, K. Prasad.....	299
<b>Dual-Phase-Lag Thermal Model of Test Microchip Structure Dedicated to Electronic Circuit Thermal Properties Estimation using Artificial Intelligence</b>	
T. Raszkowski, A. Samson, M. Zubert, M. Janicki.....	305
<b>Flip-chip ICs SEE Testing Technique</b>	
D.V. Bobrovsky, A.A. Pechenkin, A.A. Novikov, A.I. Chumakov, N.V. Ryasnoy, Y.V. Churilin ....	309
<b>Compendium of TID Influence on SEE Sensitivity Investigation</b>	
A.A. Novikov, A.A. Pechenkin, A.I. Chumakov, A.N. Tsirkov, M.P. Belova .....	313
<b>Frequency Dependence of SEU in 0.18um Processor</b>	
V.A. Marfin, P.V. Nekrasov, I.O. Loskutov, A.Y. Nikiforov .....	317
<b>Experiments on Electrical Overstress Influence on Digital ICs Depending on the Input/Output Port Configuration</b>	
A.N. Shemonaev, K.A. Epifantsev, P.K. Skorobogatov.....	321
<b>The Specialized Pulse Voltage Generator EMI-0502</b>	
A.N. Shemonaev, K.A. Epifantsev, P.K. Skorobogatov.....	325
<b>Design and Testing Issues of a High-Speed SOI CMOS Dual-Modulus Prescaler for Radiation Tolerant Frequency Synthesizers</b>	
D.I. Sotskov, V.V. Elesin, K.M. Amburkin, G.N. Nazarova, N.A. Usachev, A.Y. Nikiforov .....	329
<b>SPICE-Level Layout-Aware Single Event Effects Simulation of Majority Voters</b>	
A.O. Balbekov, M.S. Gorbunov, G.I. Zebrev .....	333
<b>Author Index</b>	337